

**IEEE SW Test Workshop**  
Semiconductor Wafer Test Workshop



**Ellis Huang**  
**MPI CORPORATION**

**Novel Vertical Probe Card Solution for  
Multi-DUTs and RF Device on 3GHz  
Applications**



**June 6 to 9, 2010**  
**San Diego, CA USA**

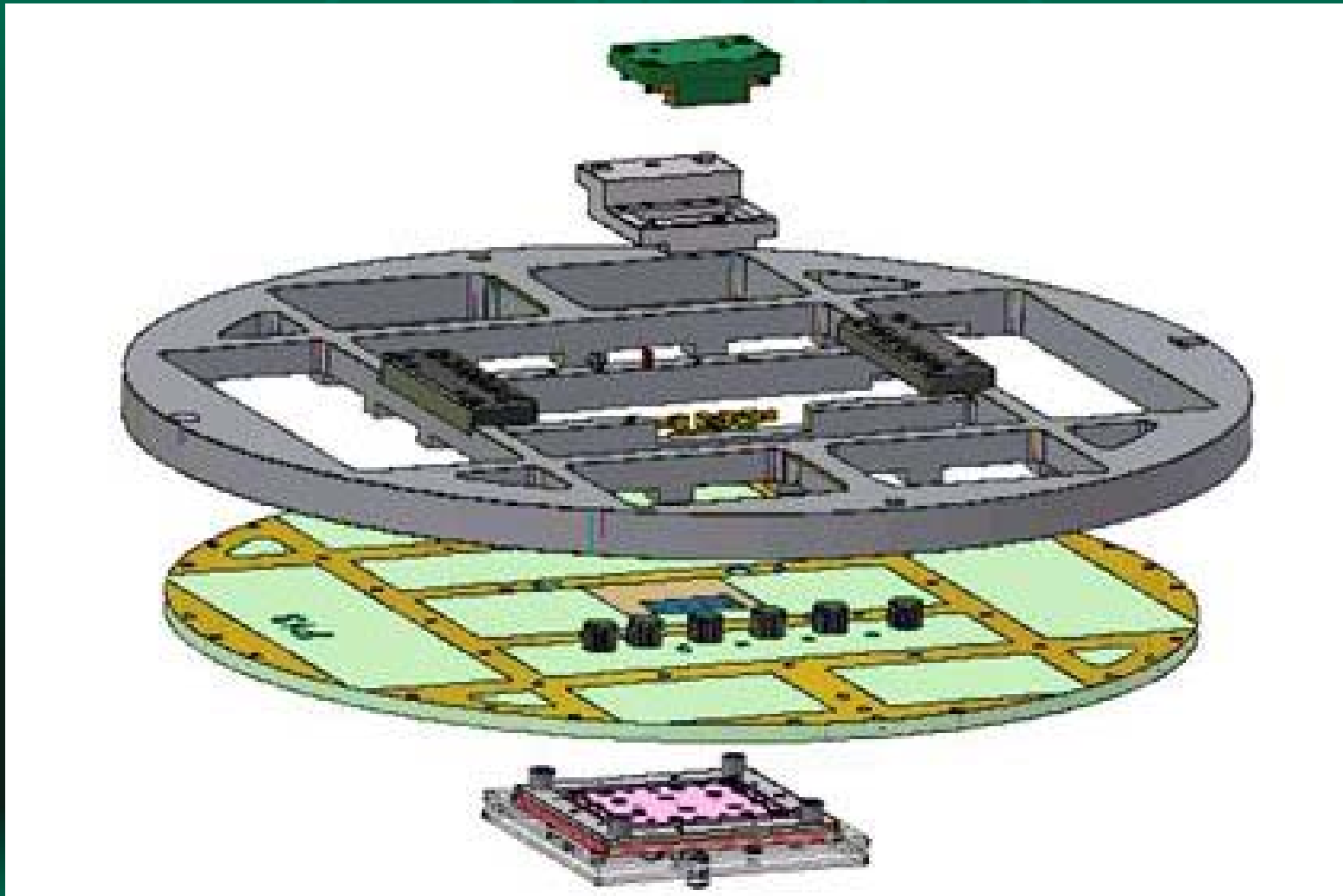
# Overview

- **VPC Structure of MPI**
- **RF Simulation and Modeling**
- **Performance on 4-DUTs RF VPC**
- **Summary**



# VPC Structure of MPI

## □ MPI INT VPC Structure (Side view)

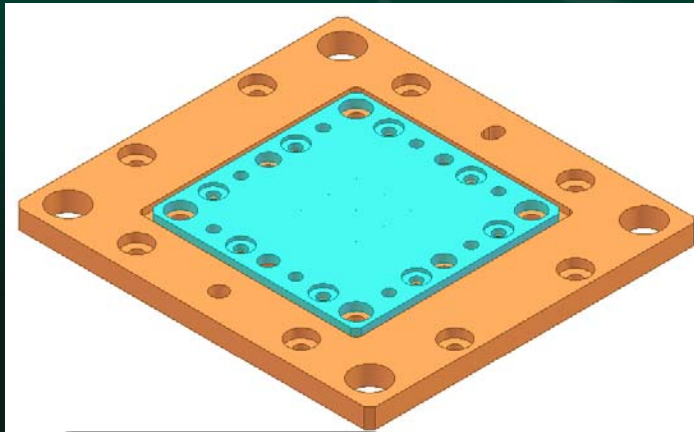


# VPC Structure of MPI

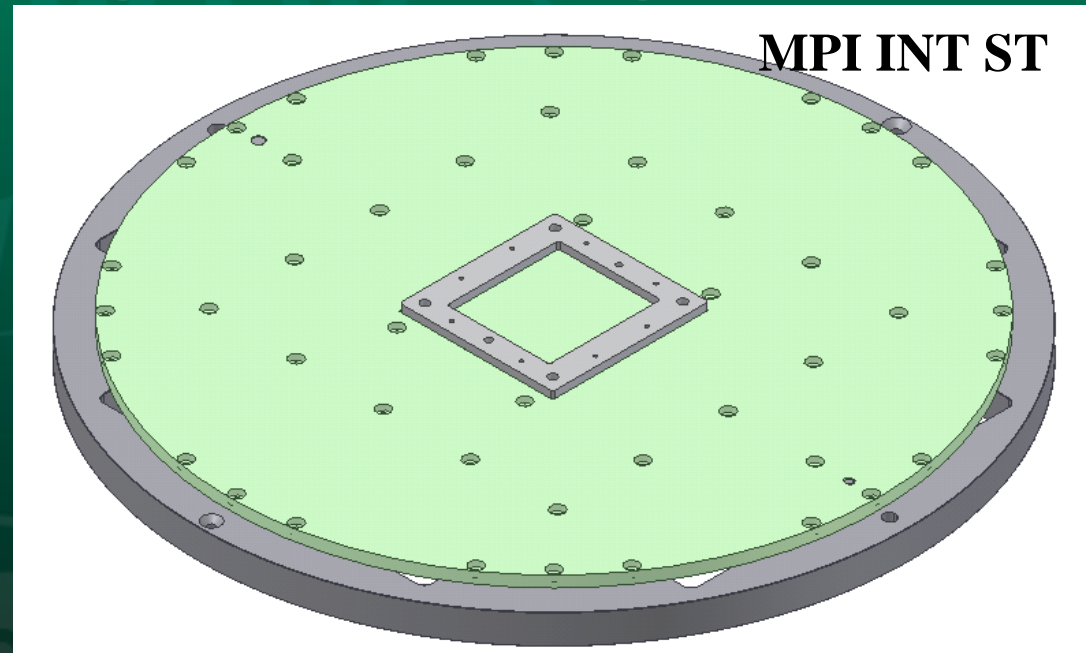
## □ MPI INT VPC Structure (wafer side view)

MPI RF PH

(use 3mil Flat tip Needle)



*RFPH Patent Issued*



MPI INT ST

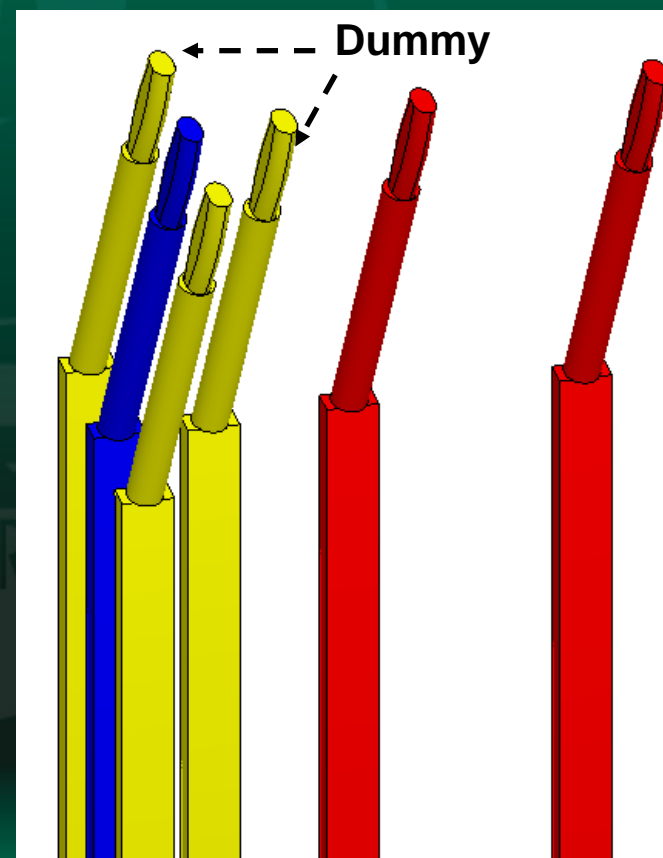
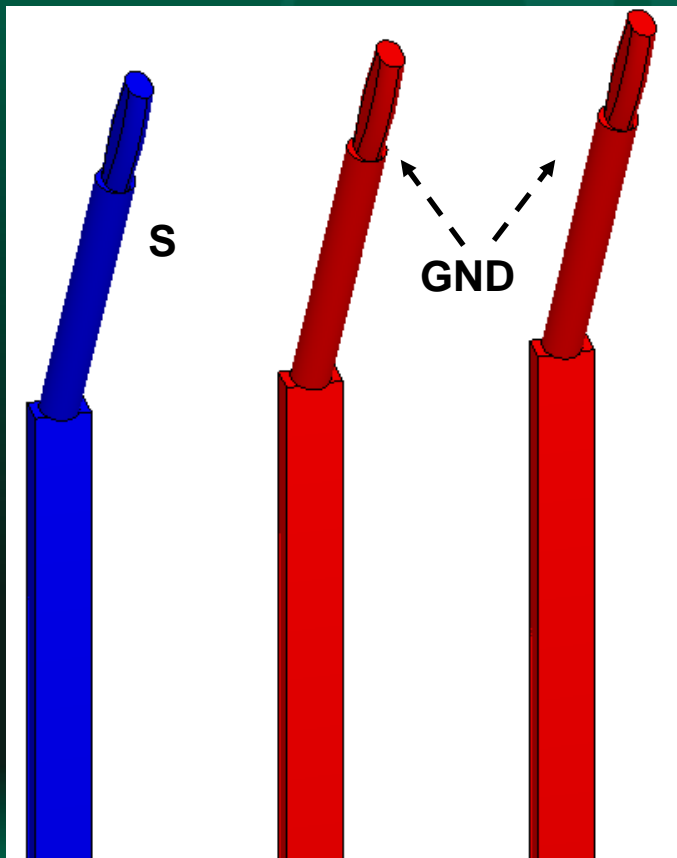
*INT Patent Issued*



# VPC Structure of MPI

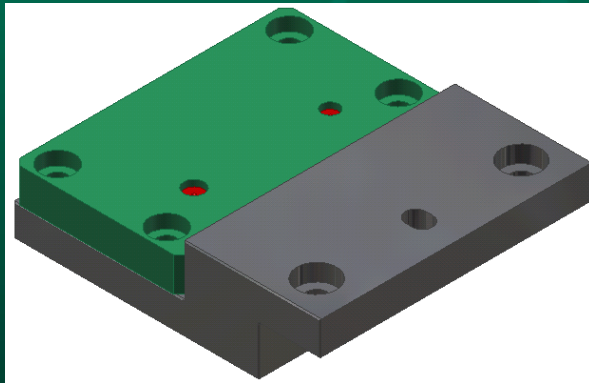
## □ VPC Needle Structure ( Dummy Tuning )

MPI applies dummy needles for 50 ohm impedance matching on VPC PH.

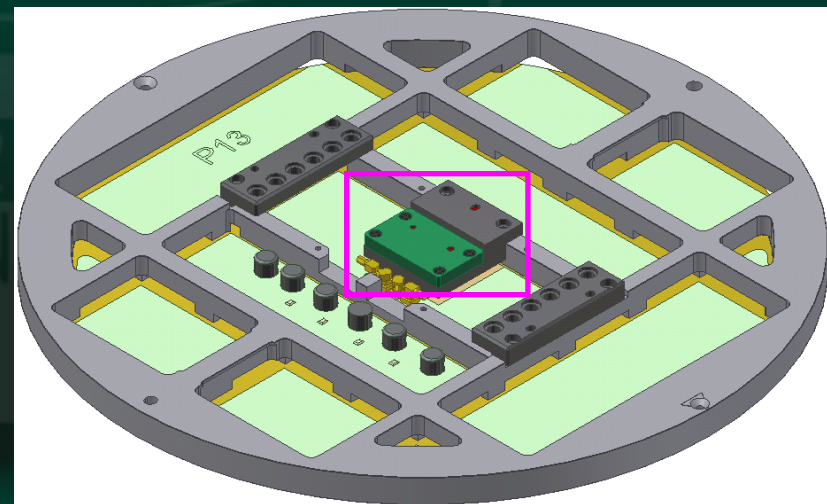


# VPC Structure of MPI

## □ MPI INT VPC Structure – Matching tooling



**RF matching tooling**



**(Tester side view)**

*MPI Patent Pending*



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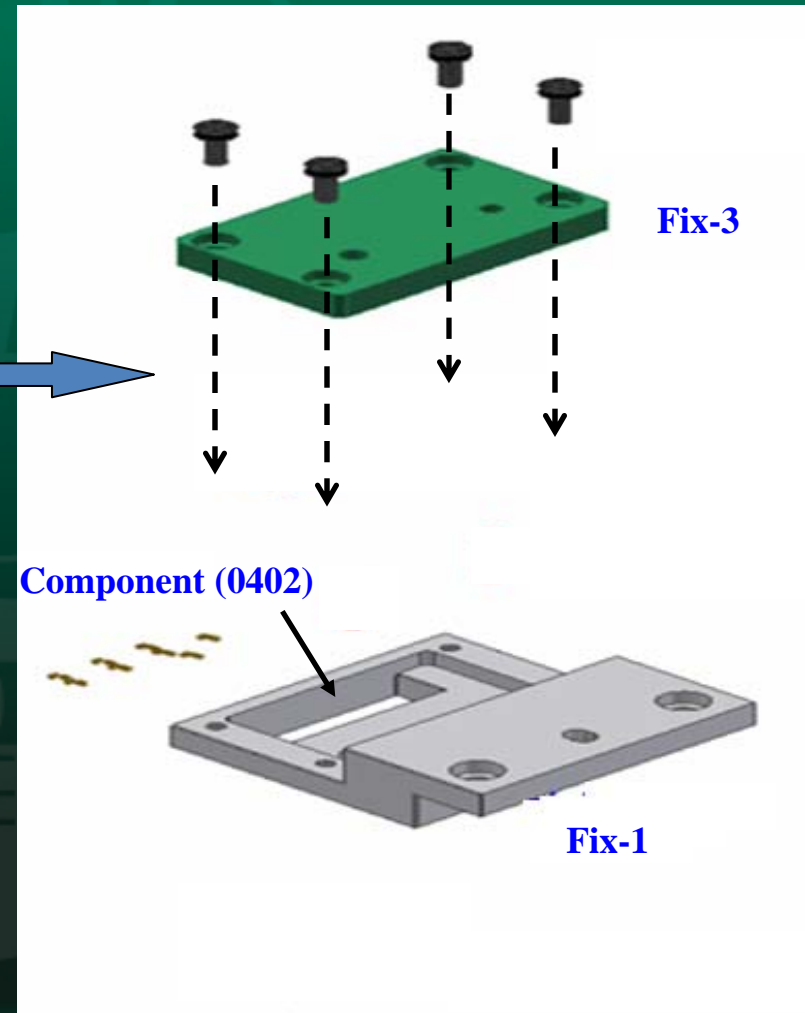
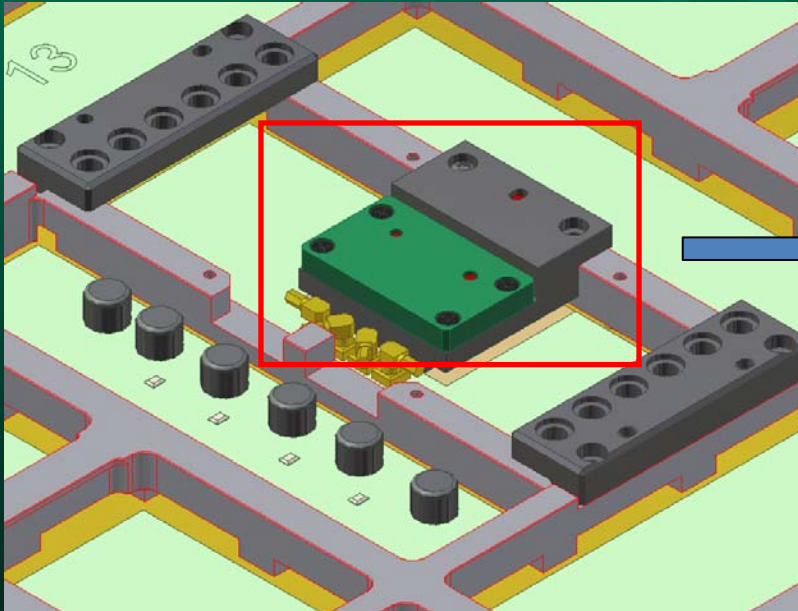
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# VPC Structure of MPI

## □ MPI INT VPC Structure

RF matching tooling tester side view



**Saving the engineering time from  
1-hour to 10-mins in clean room !**

RF matching tooling assembly



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# RF Simulation and Modeling

For RF application, the electrical simulation or modeling of each element is very important for impedance matching and power optimization.

## Modeling Elements:

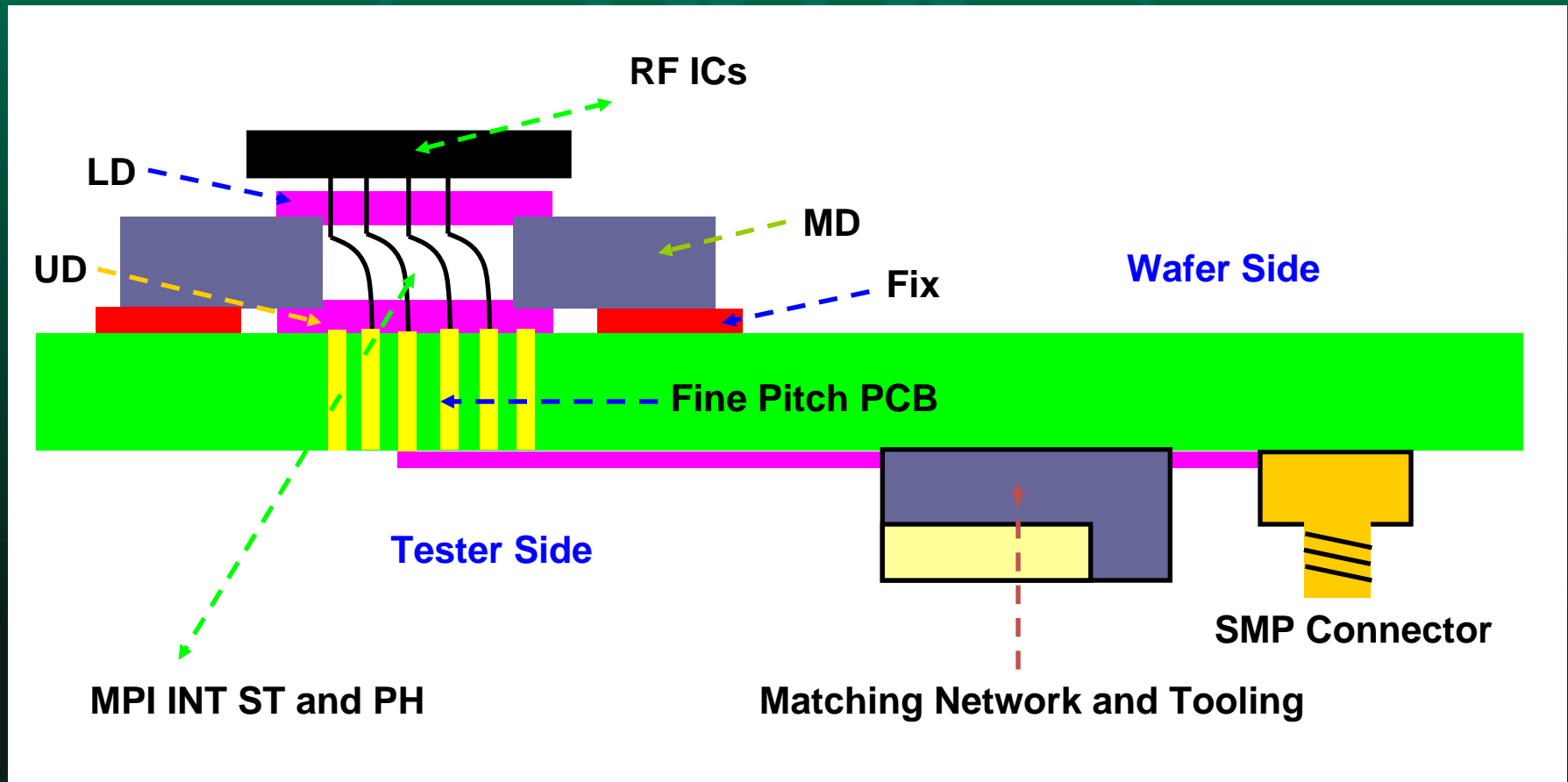
- a. The Matching Network and Tooling
- b. RF trace on PCB
- c. The Effects of Through Vias
- d. RF PH
- e. Chip Impedance





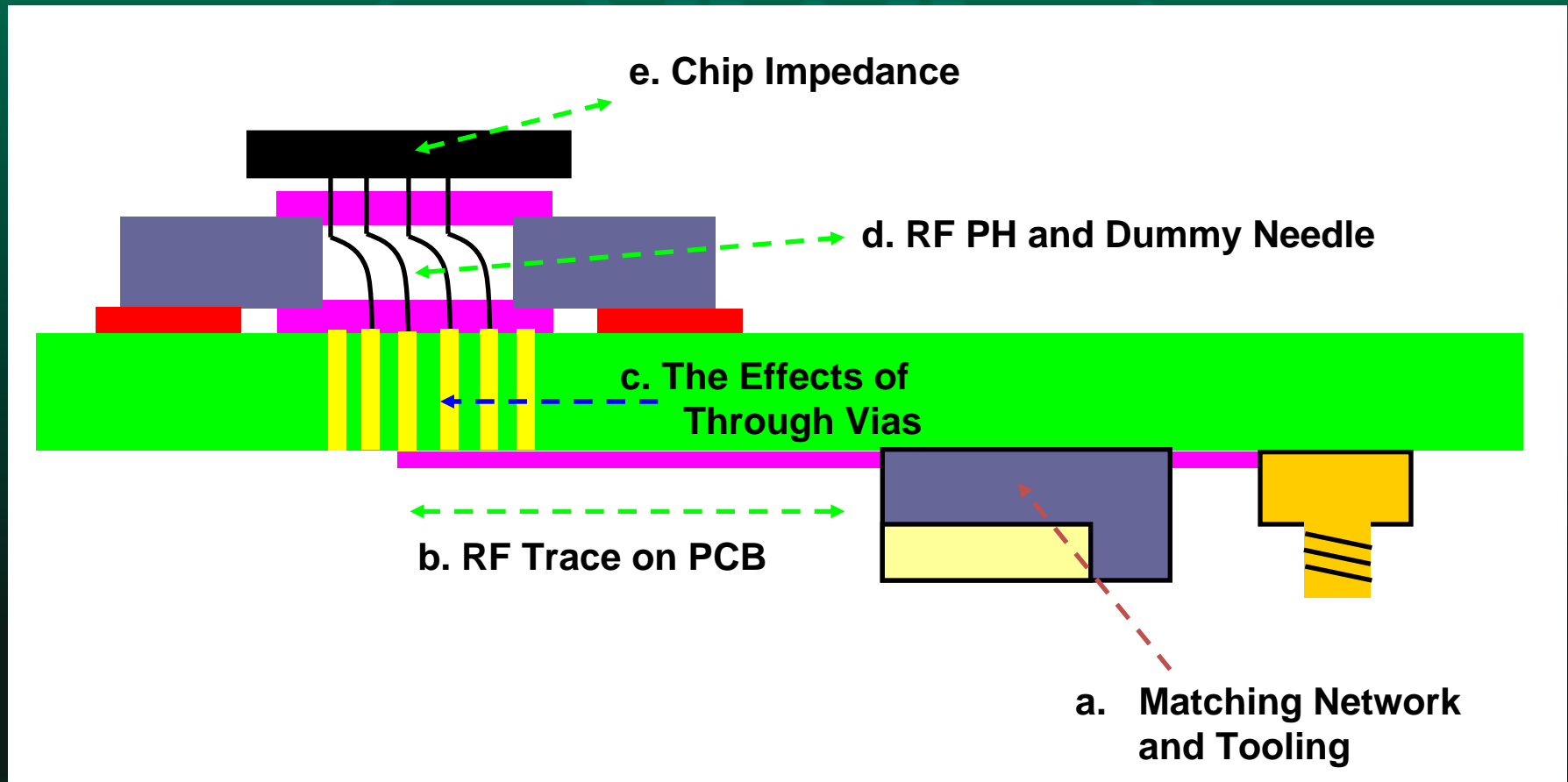
# VPC Structure of MPI

## □ MPI INT VPC Structure (Side view)



# RF Simulation and Modeling

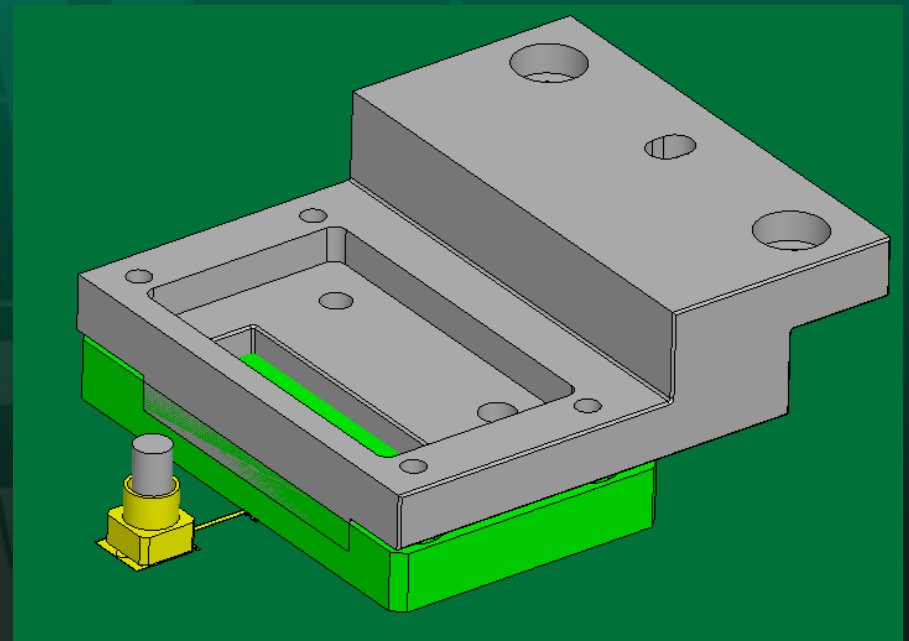
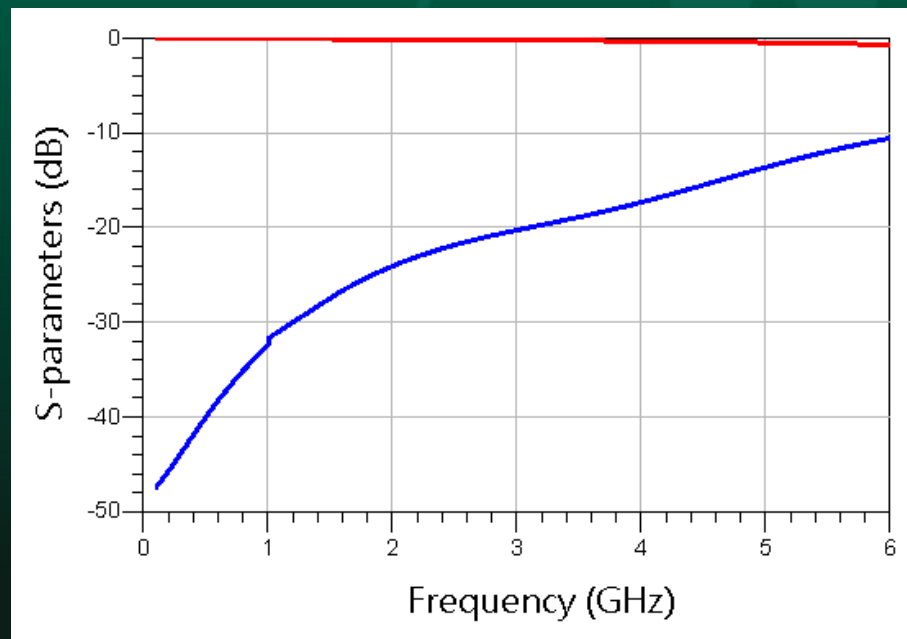
## □ MPI INT VPC Structure (Side view)



# RF Simulation and Modeling

- Simulation of PCB Traces with Matching tooling

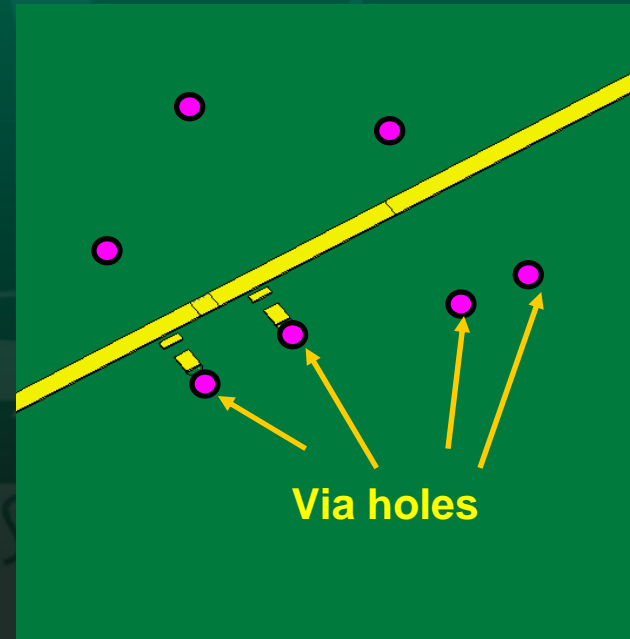
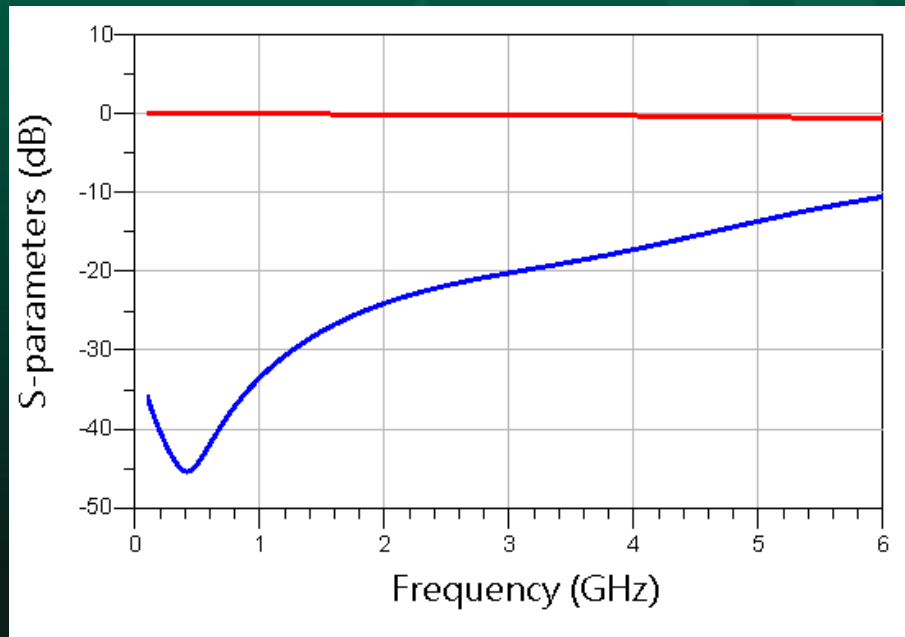
**Matching tooling bandwidth is up to 6 GHz**



# RF Simulation and Modeling

- Simulation of PCB Traces with Via holes

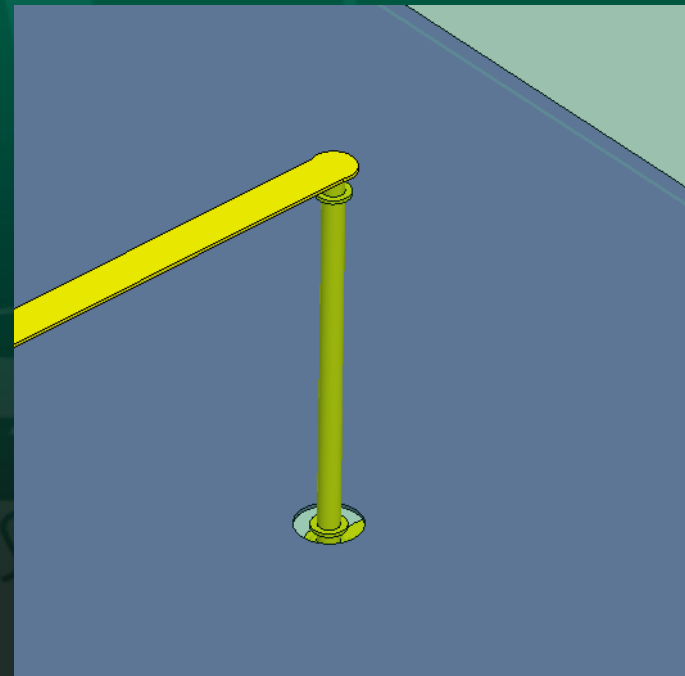
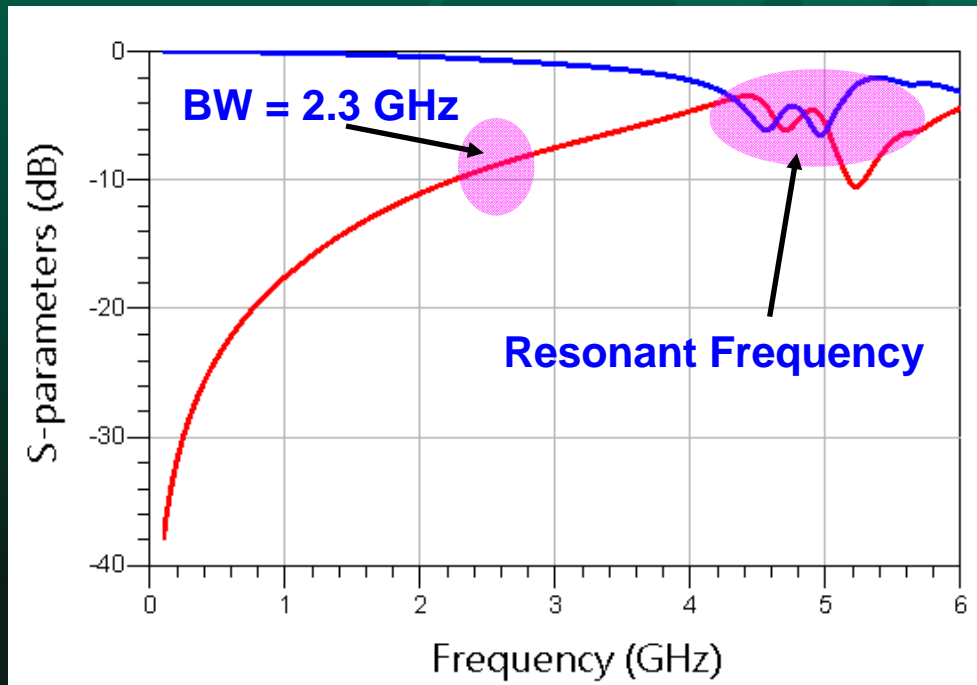
**RF trace bandwidth is up to 6 GHz**



# RF Simulation and Modeling

- Simulation of Vias, coaxial Vias (1)

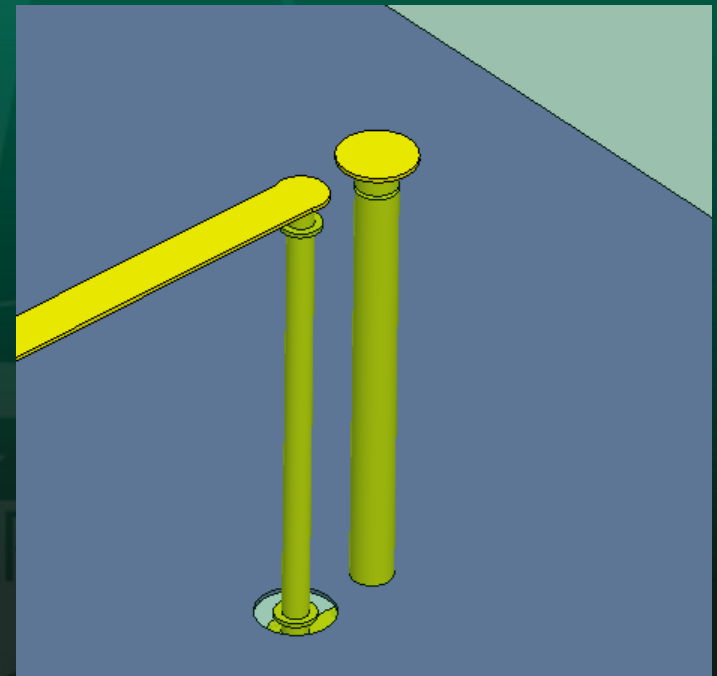
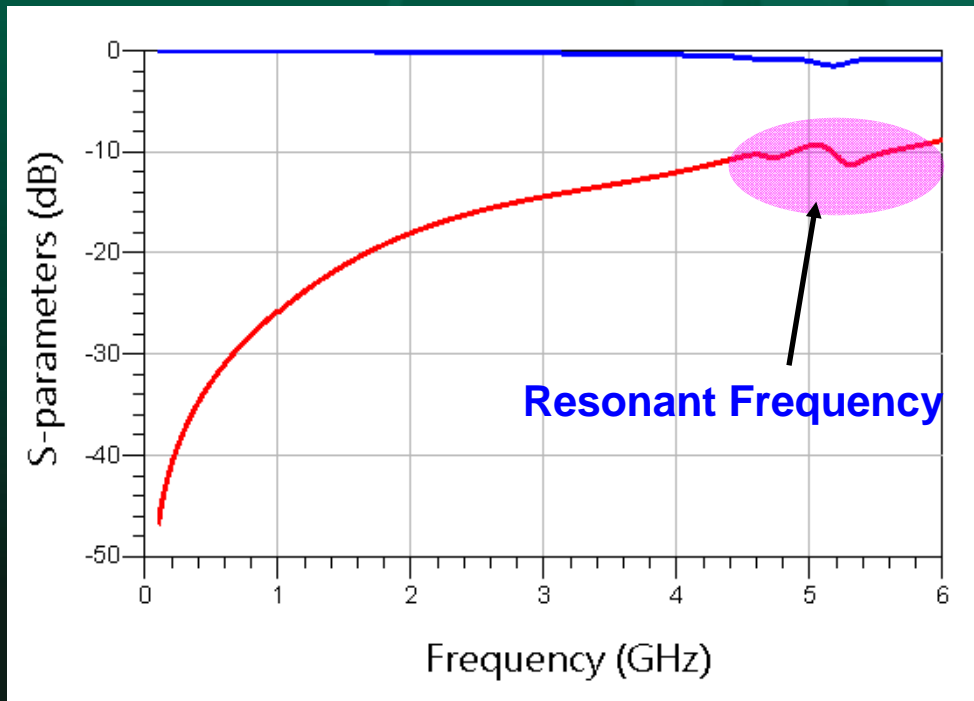
The inductance effects on a through via.



# RF Simulation and Modeling

- Simulation of Vias, coaxial Vias (2)

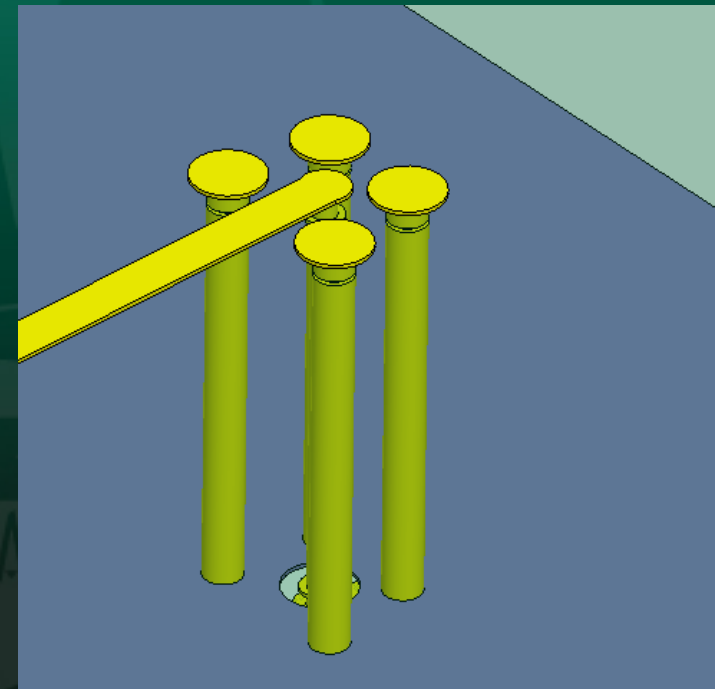
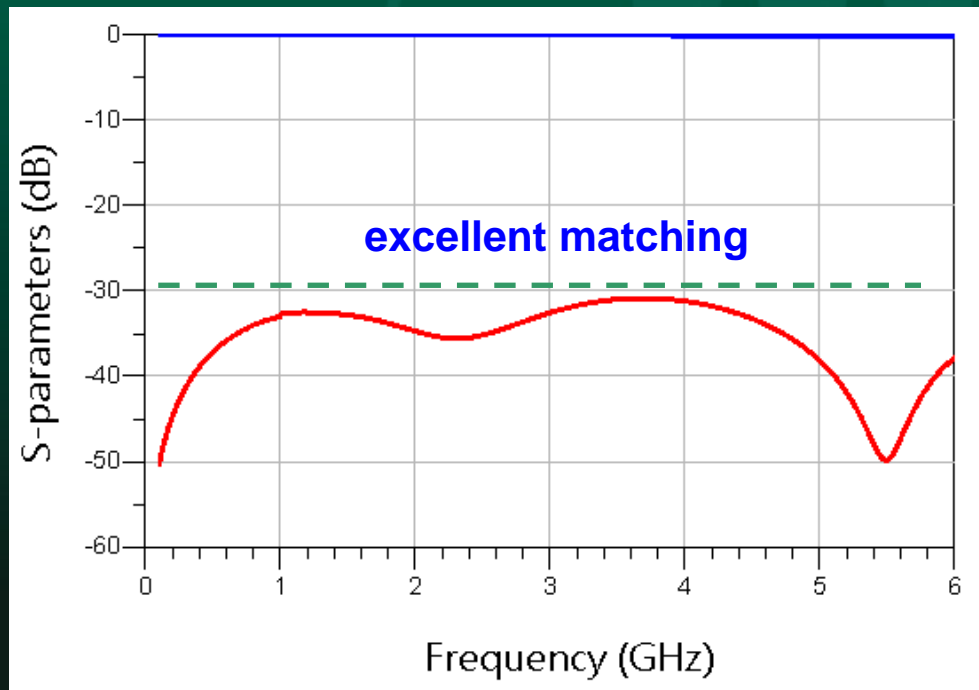
Coaxial via improves the bandwidth to 4.5 GHz



# RF Simulation and Modeling

- Simulation of Vias, coaxial Vias (3)

Optimization of coaxial vias could remove the resonant frequency.

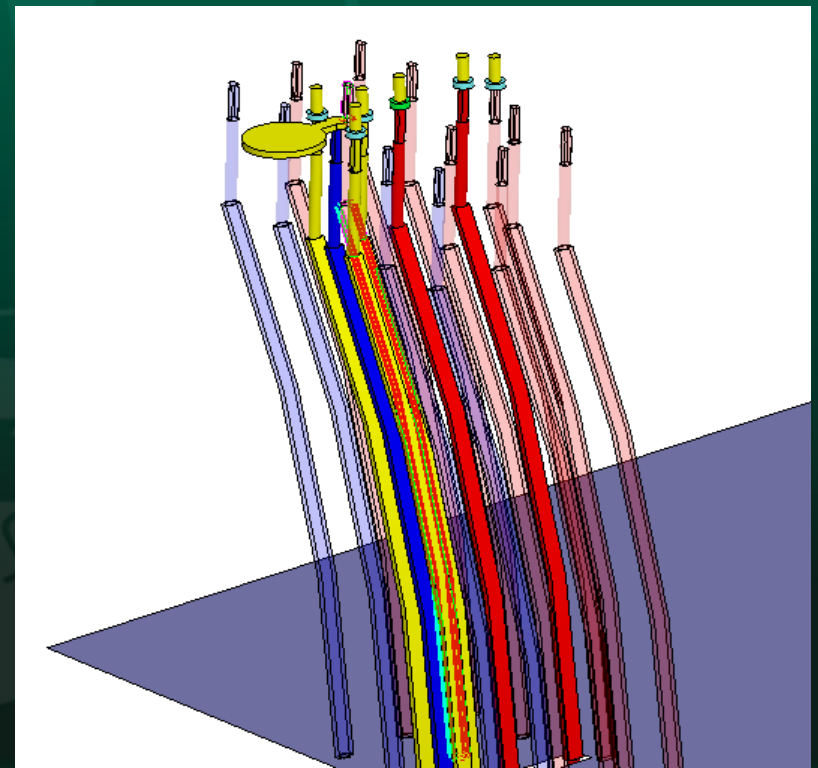
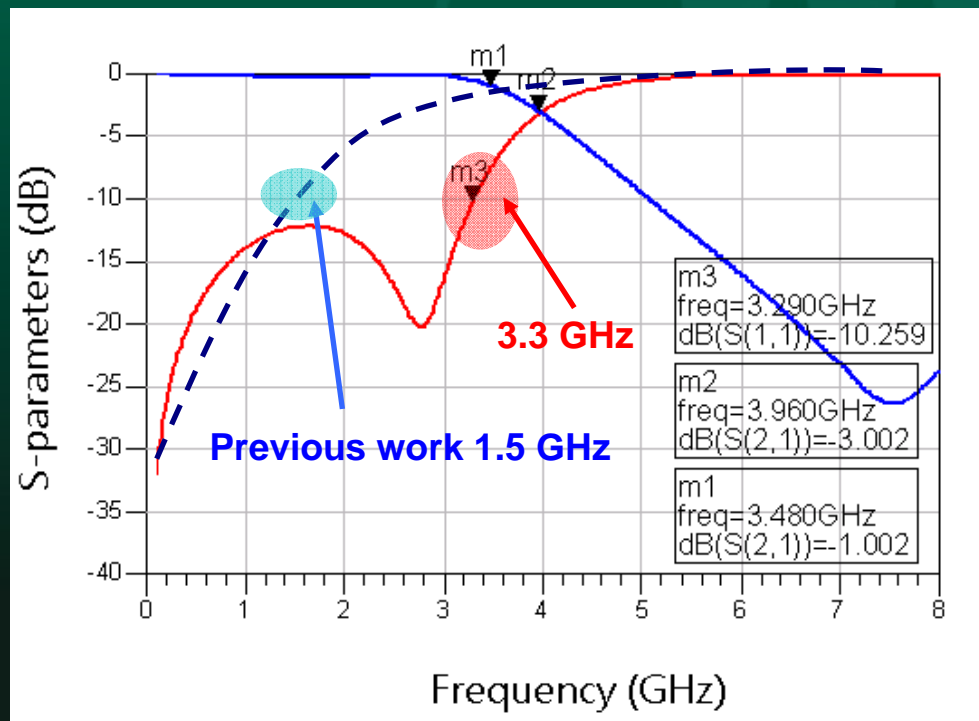




# RF Simulation and Modeling

- Simulation of Signal and Dummy Needles

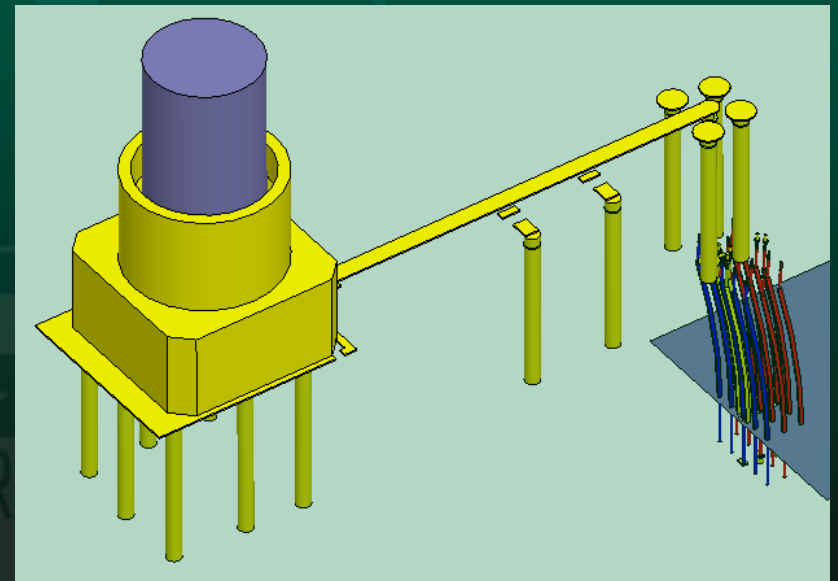
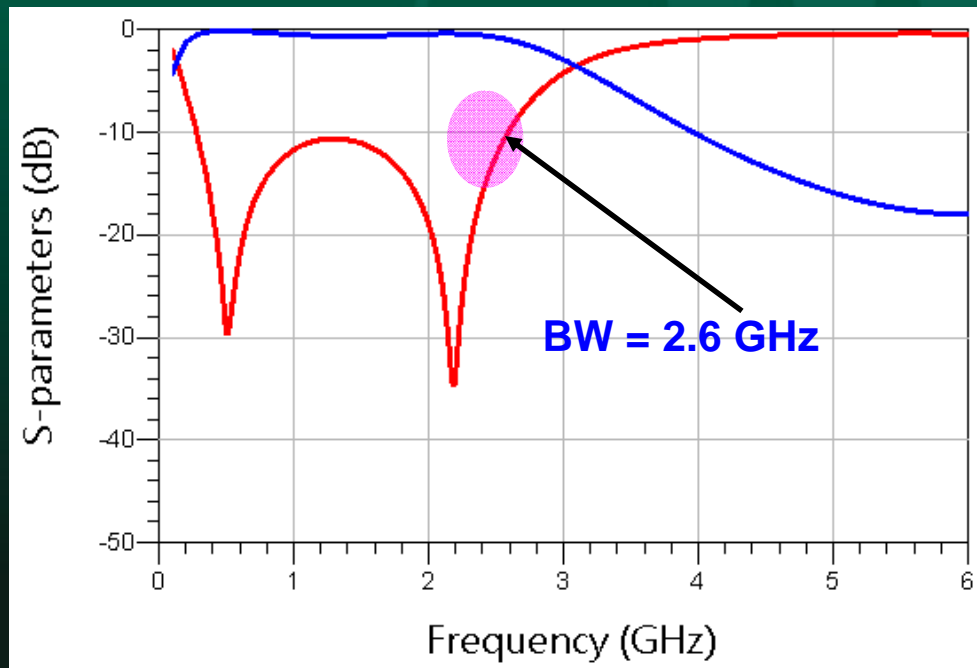
The bandwidth characteristic of MPI vertical PH structure.



# RF Simulation and Modeling

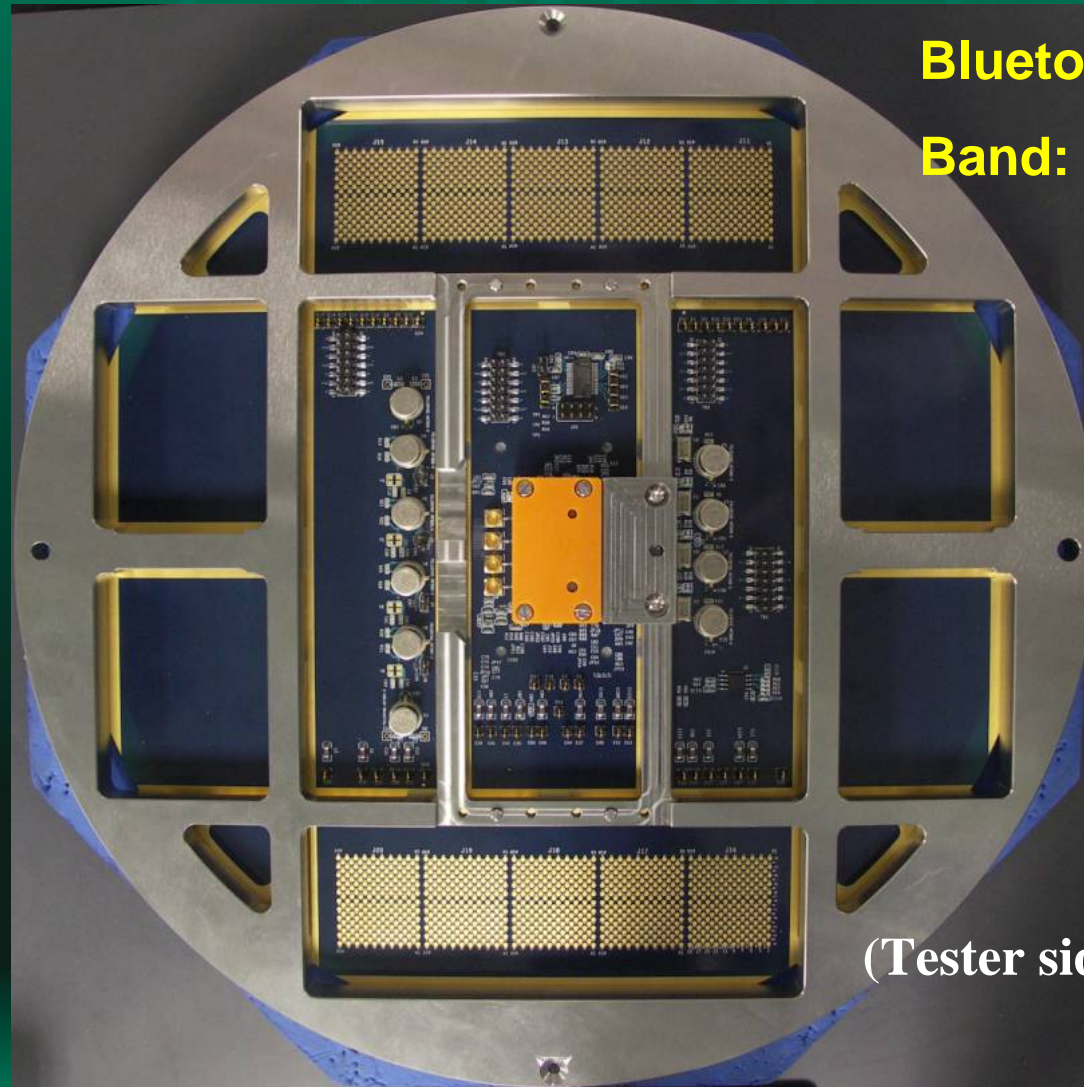
- Simulation of Total RF Path

**RF bandwidth of total transmission paths is about 2.6 GHz**



# Performance on 4-DUTs RF VPC

□ MPI INT VPC Photo



Bluetooth Application

Band: 2400~2500 MHz

(Tester side view)



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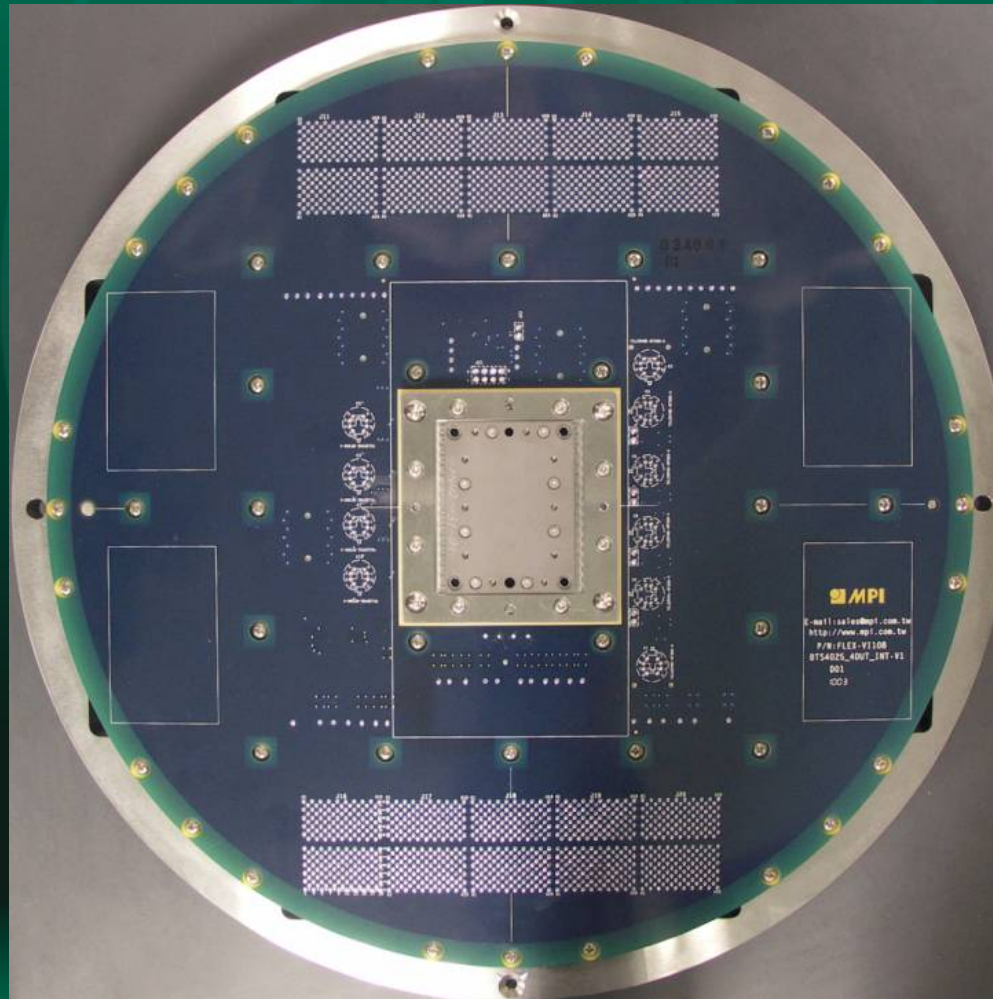
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# Performance on 4-DUTs RF VPC

□ MPI INT VPC Photo

(Wafer side view)



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# Performance on 4-DUTs RF VPC

## Impedance Measurement Using ENA



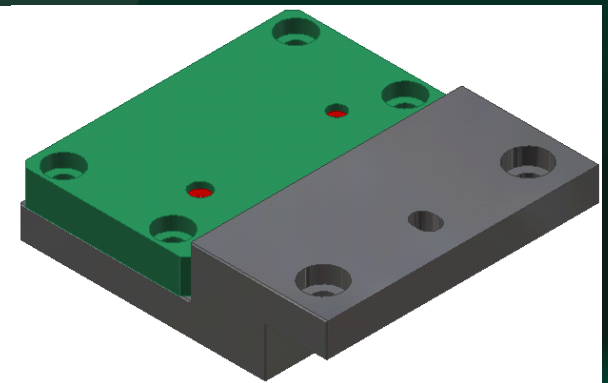
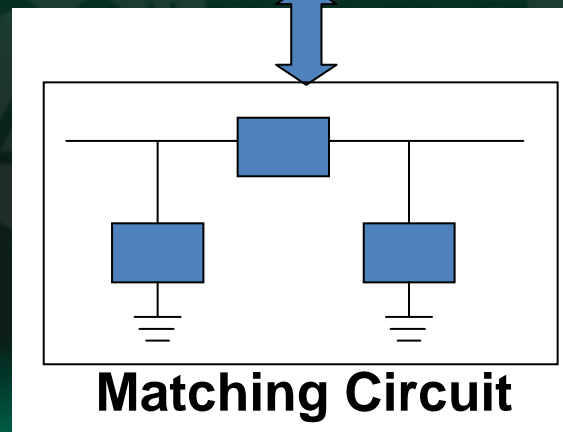
**Initial NB**



**Prober**



**ENA**



**RF matching tooling**

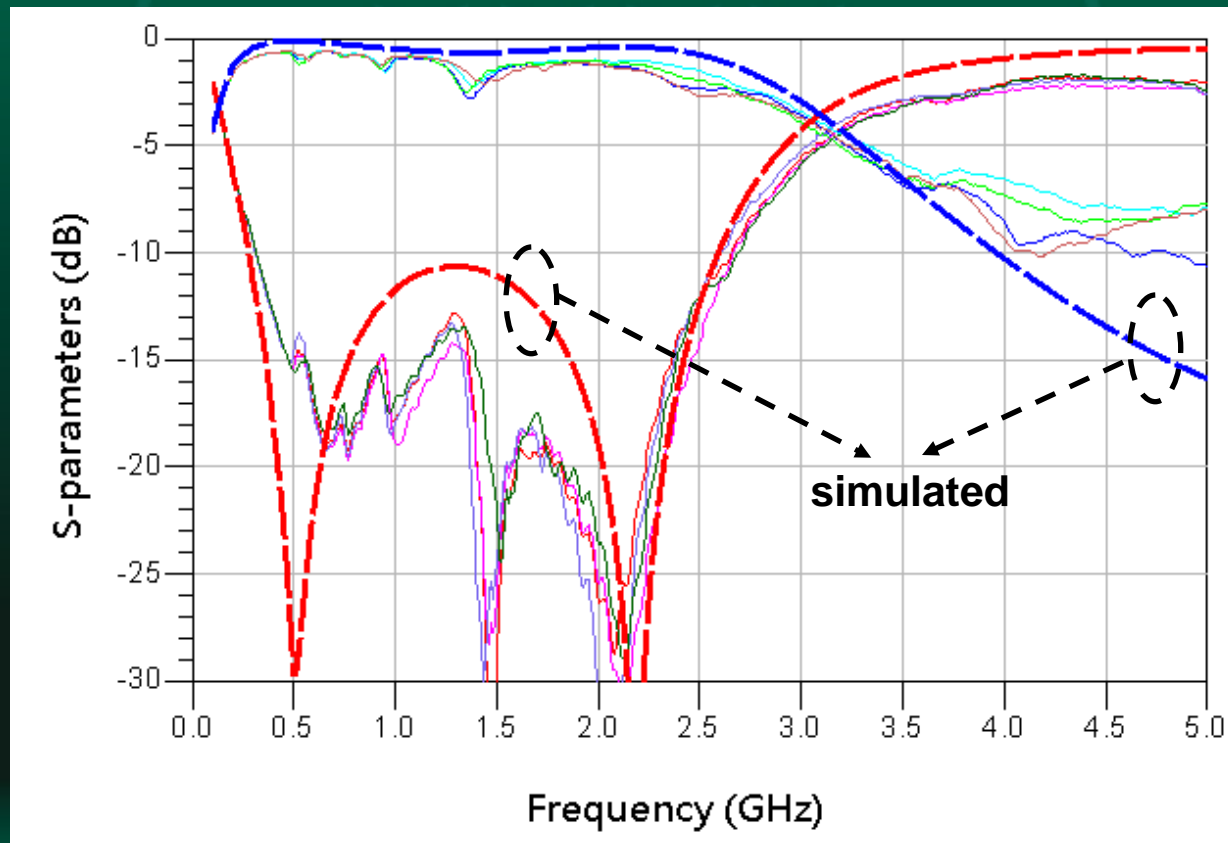




# RF Simulation and Modeling

Performance of each site using 50 ohm test board.

Measured SITE #0~3 vs Simulated



# Performance on 4-DUTs RF VPC

## Power Measurement Using EXA



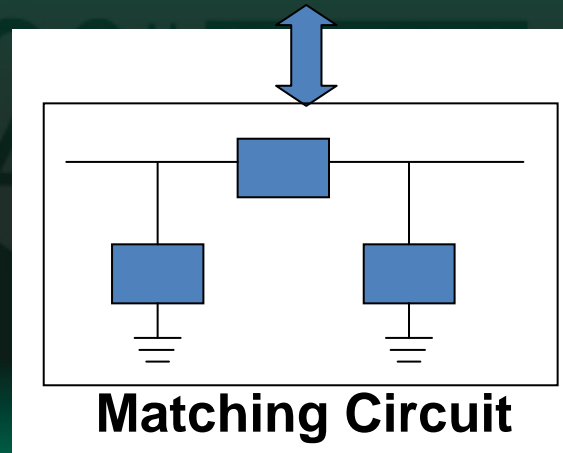
**Initial NB**



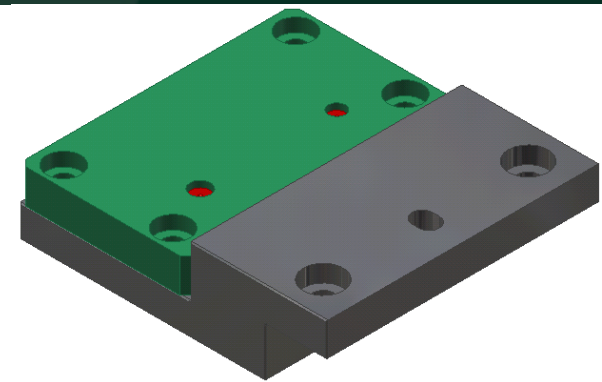
**Prober**



**EXA**



**Matching Circuit**



**RF matching tooling**

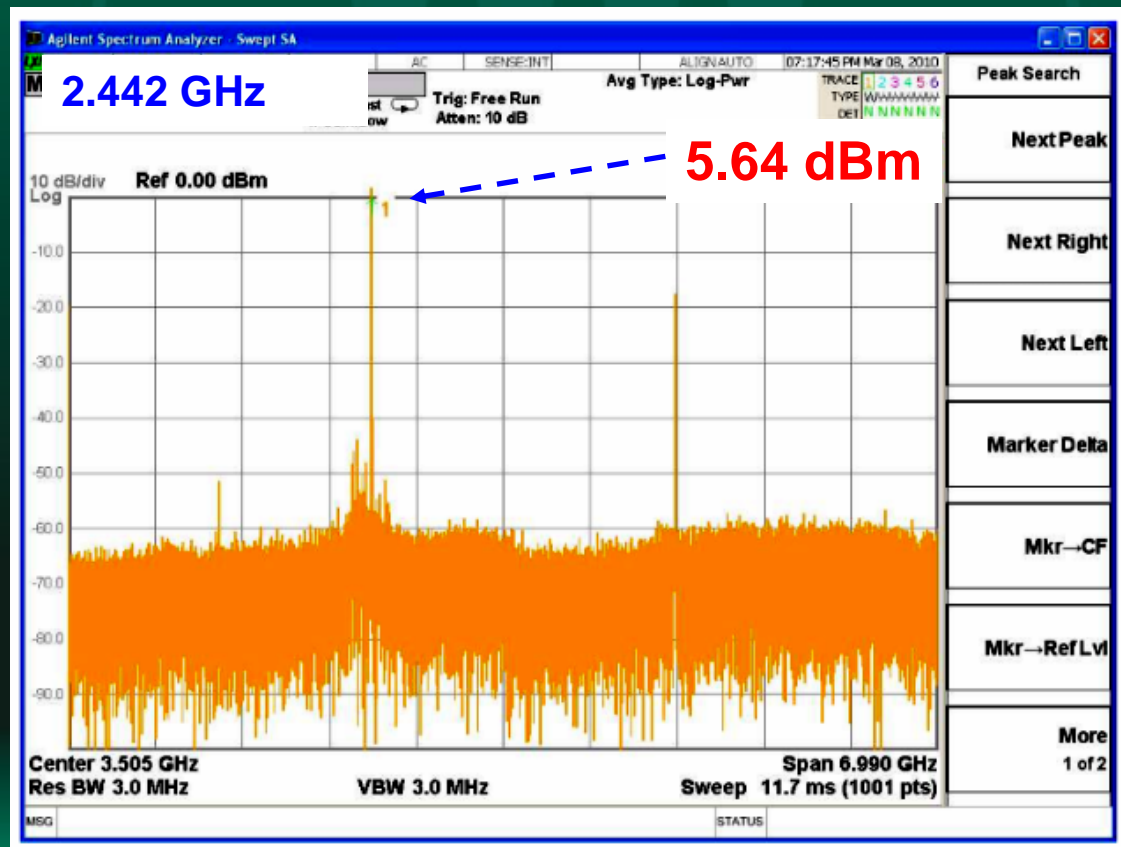




# Performance on 4-DUTs RF VPC

- Power level of Contacting the Bluetooth Chip

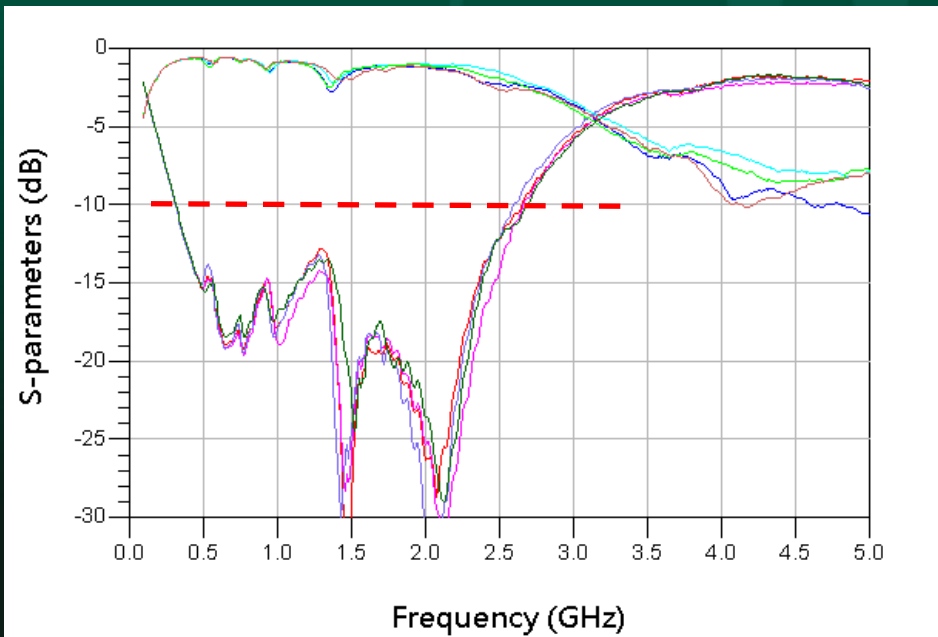
Is there room for power level improvement ?



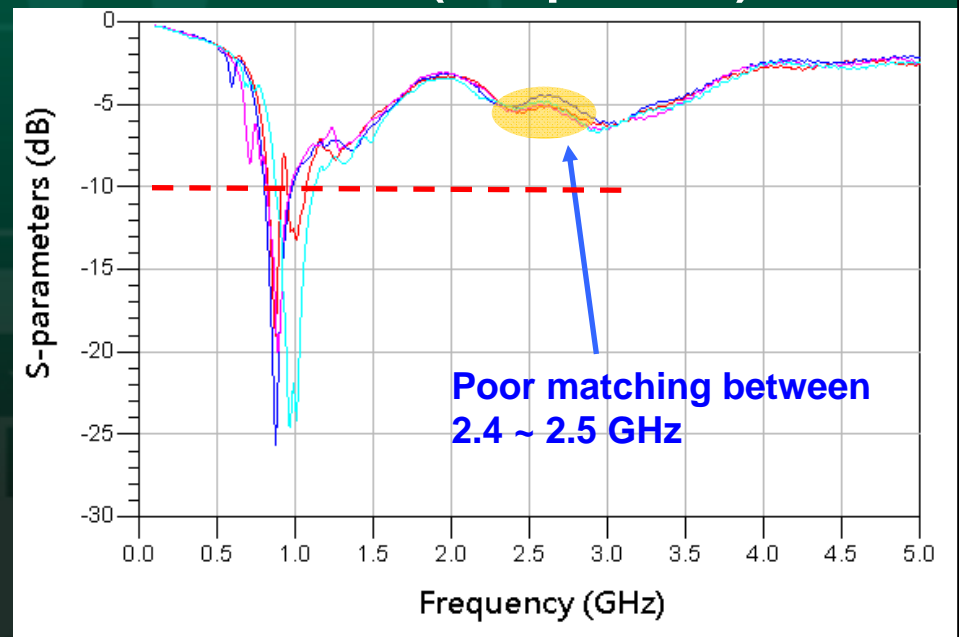
# Performance on 4-DUTs RF VPC

- The Frequency Characteristic  
Poor return loss due to the realistic IC impedance

SITE # 0~3 ( 50  $\Omega$  Load )



SITE # 0~3 ( Chip Load )



Contact standard test board

Contacting RF chip



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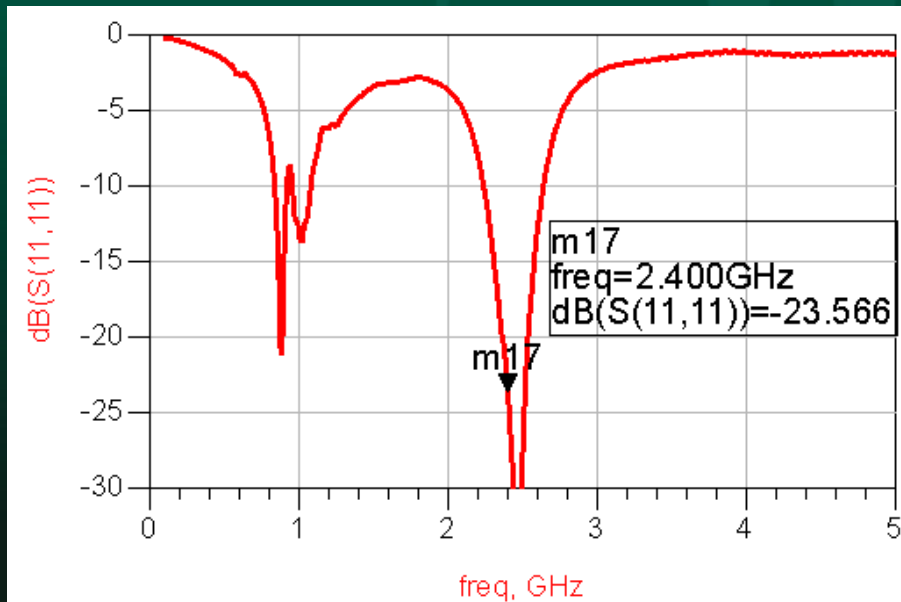
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# Performance on 4-DUTs RF VPC

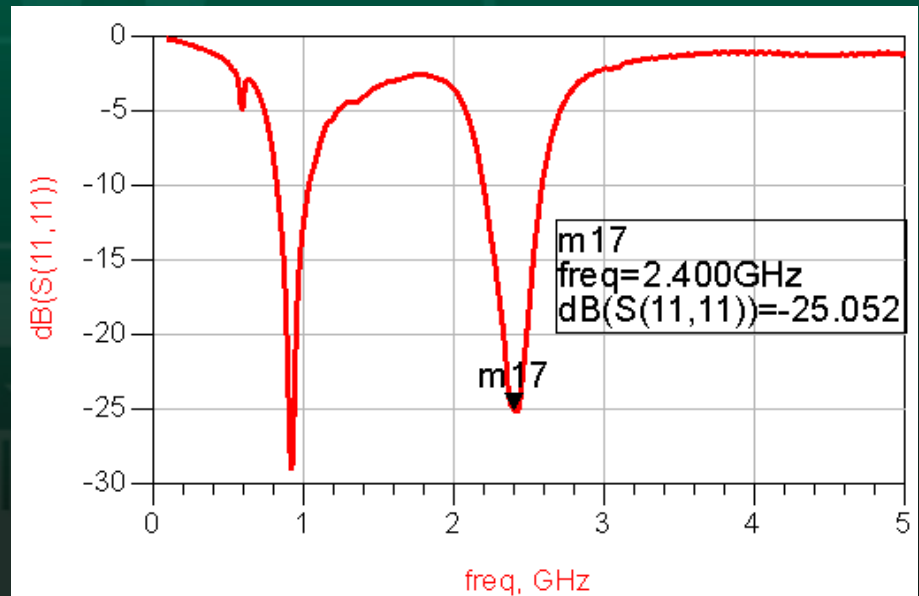
- The Frequency Characteristic (after re-matching)

SITE # 0 , Chip Load



Contacting RF chip

SITE # 1 , Chip Load



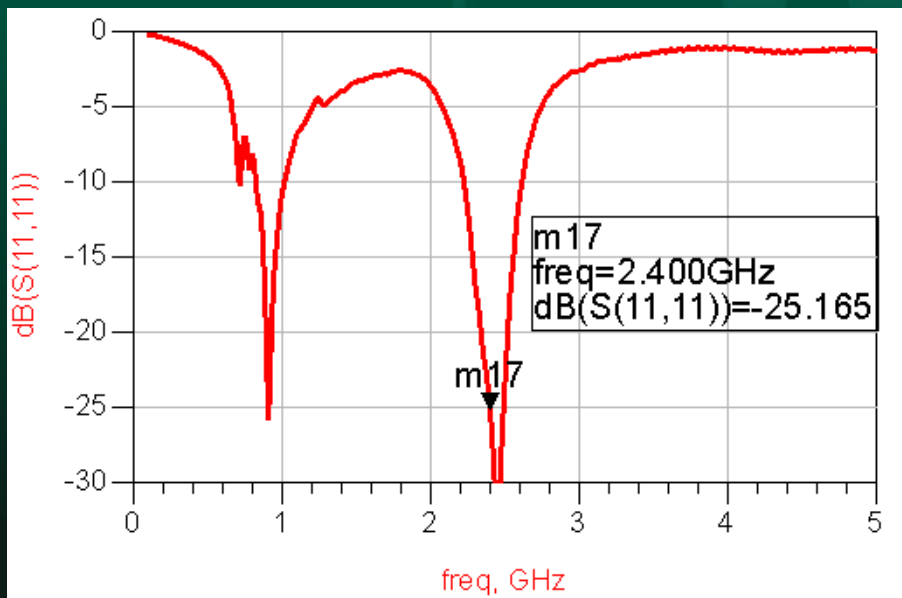
Contacting RF chip



# Performance on 4-DUTs RF VPC

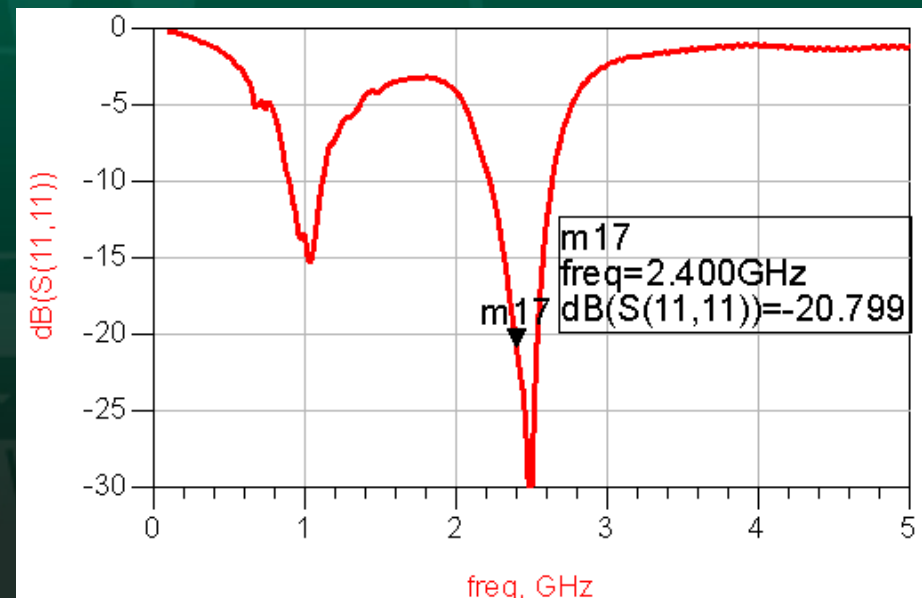
- The Frequency Characteristic (after re-matching)

SITE # 2 , Chip Load



Contacting RF chip

SITE # 3 , Chip Load



Contacting RF chip

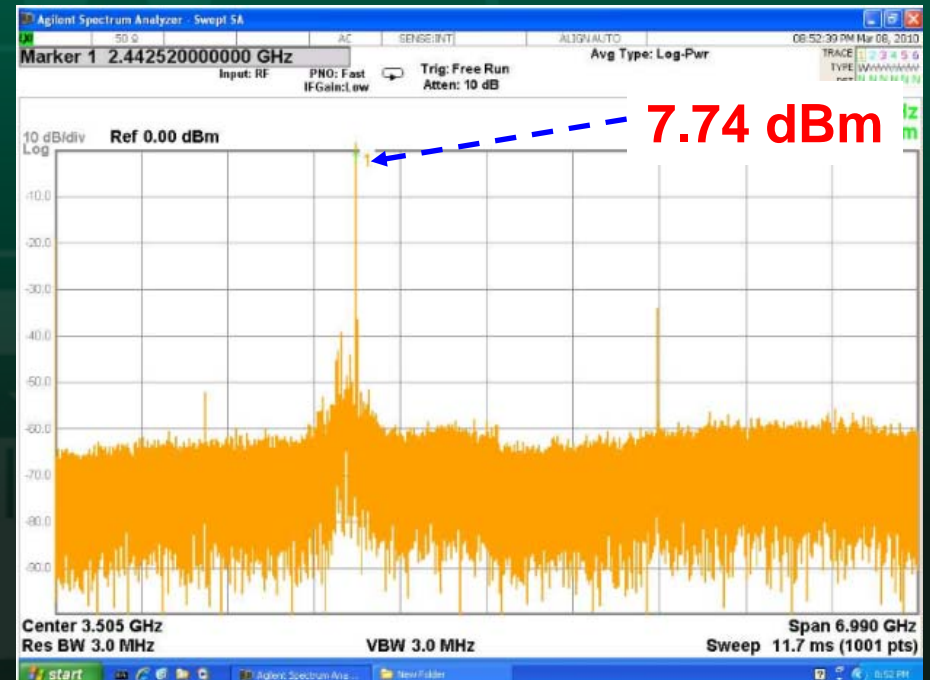
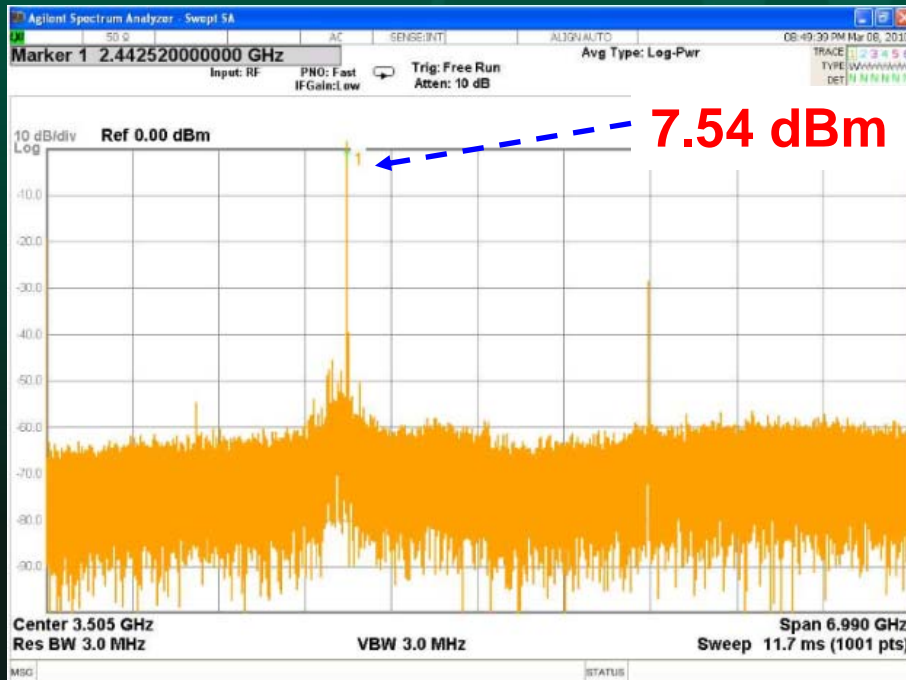


# Performance on 4-DUTs RF VPC

- Power Level for All DUTs

SITE # 0

SITE # 1

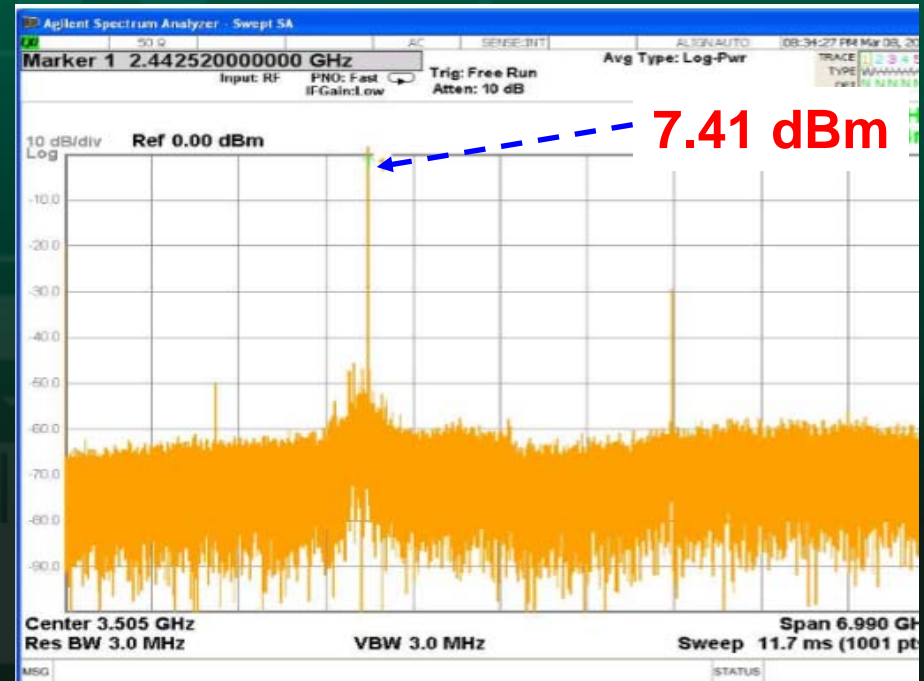
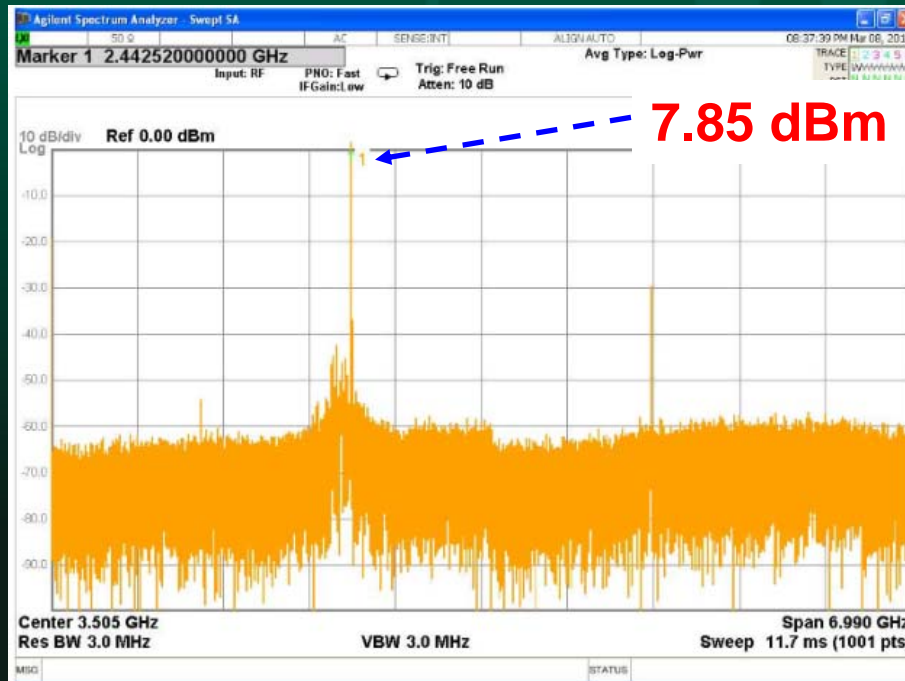


# Performance on 4-DUTs RF VPC

- Power Level for All DUTs

SITE # 2

SITE # 3



# Performance on 4-DUTs RF VPC

- Power Level for All DUTs

Input testing signal is 9dBm

|        | Power (dBm) | S11@2.45 G (dB) | Bandwidth (GHz) |
|--------|-------------|-----------------|-----------------|
| Site 0 | 7.54        | -33             | 2.24G ~2.63     |
| Site 1 | 7.74        | -23             | 2.2G ~ 2.58     |
| Site 2 | 7.85        | -31             | 2.23G ~ 2.61    |
| Site 3 | 7.41        | -24             | 2.23G ~ 2.63    |

The measured results depict the power loss of total RF signal path is around 1.5 dB , and the bandwidth characteristic could satisfy the Bluetooth (BT) application at 2.4 GHz .





# Summary

- Further improvement of VPC RF bandwidth.
  - Upgrade BW from 3 GHz to 5 GHz
- 8-DUT RF Vertical Probe Card
  - 2010 4-DUTs release.
  - 2011 8-DUTs release.



# Acknowledgements

Great thanks to teamwork :

Ariel Shih, Thompson Hsu, Yong Feng Lin, Eason Chen,  
Jr Ping Huang (United Microelectronics Corporation)

Morgan Ku, Phil Hsieh, Anderson Huang, Joey Wu, Cahris Lin, Maureen Tsai  
(MPI Corporation)



**Thank you very much .**



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